

July/13/2021 INTT meeting

# Investigation of the half entry issue at the RIKEN testbench

RIKEN, RBRC

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H. Imai, Y. Nakamura, G. Nakano



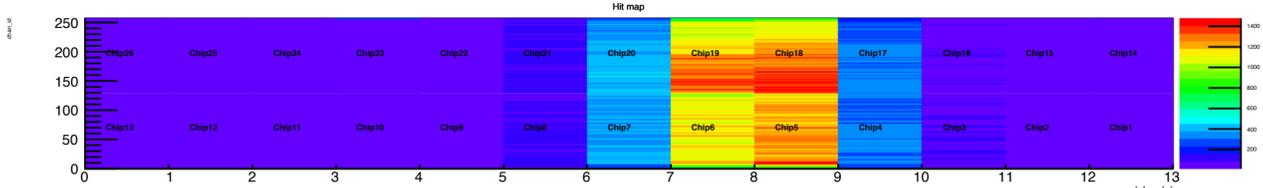
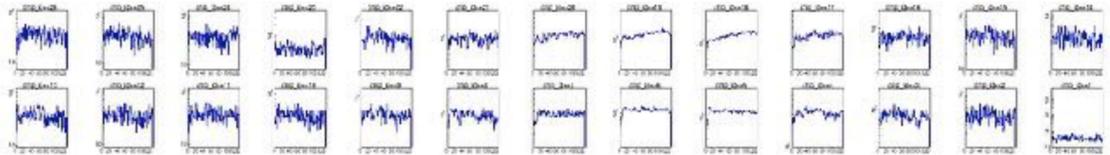
# What was done after launching

## Calibration tests

- delay configuration: 5 was found to be the best
- mass measurements with various conditions:

## $\beta$ -ray measurement

- successfully performed with/without an external scintillator trigger in June



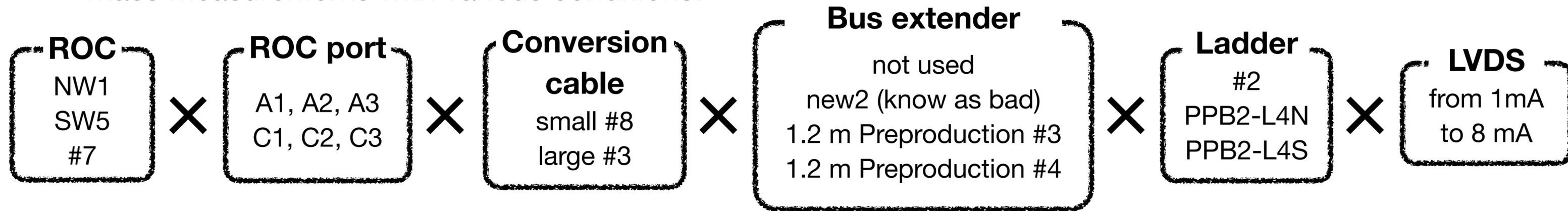
## Cosmic ray measurement

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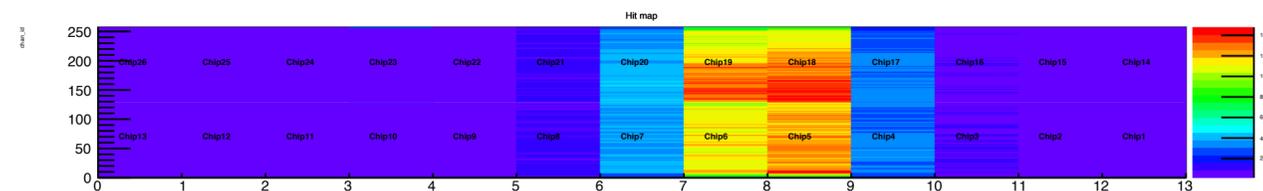
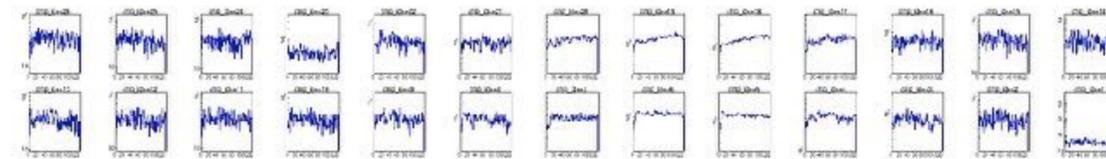
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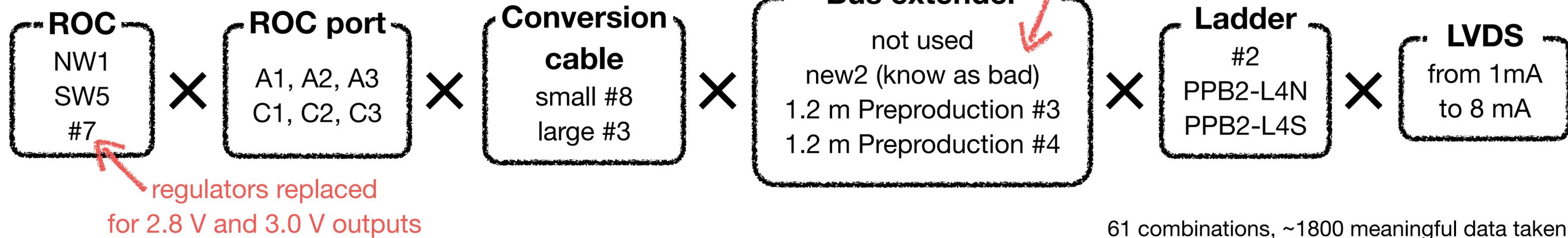
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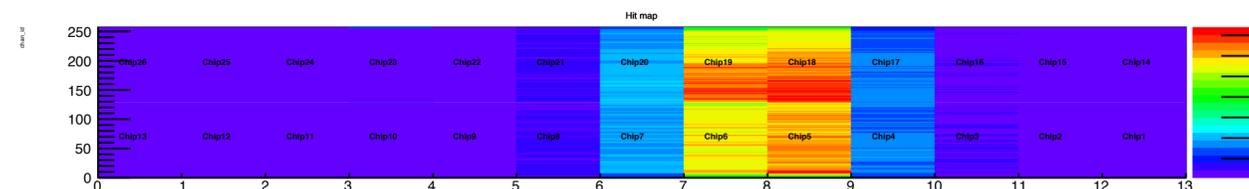
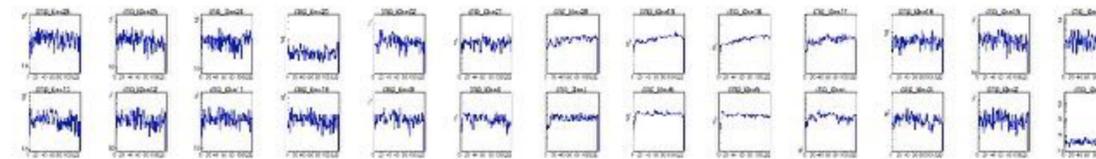
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## Cosmic ray measurement

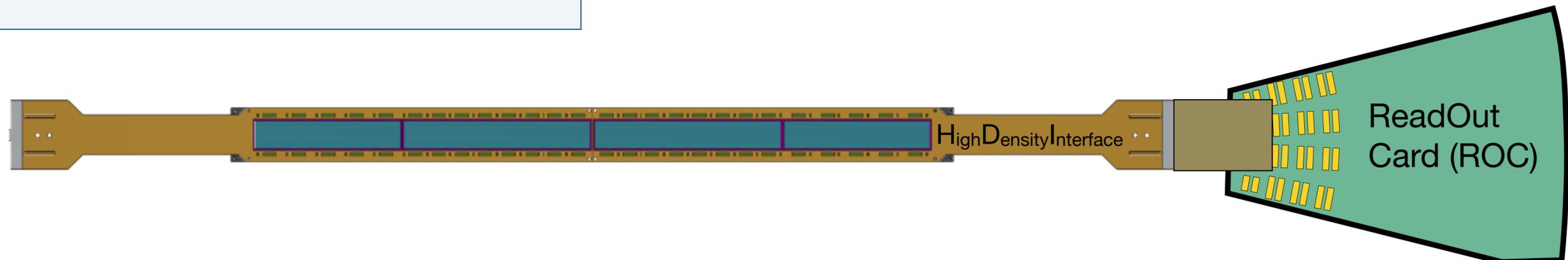
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# Calibration tests without a bus extender

Measurements were performed without any major problems.

Performance of ROC ports

	A1	A2	A3	C1	C2	C3
7	Good except chip25	no data	Good except chip1-5	Good except chip15	Good	Good
NW1	no data	no data	no data	Good	Good	Good
SW5	Good	Good	Good	Good	Good	Good



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## Setup

Ladder: PPB2-L4S  
 ROC, port: SW5, C3  
 Conversion cable: small 8  
 Bus extender: 1.2 m Prepro3

**Performance of ROC SW5 port C3**

Quality LVDS (mA)	Perfect	Fine	Bad/Dirty	Half entry, lost channels	Total
1	46 92%	2 4%	2 4%	0 0%	50 100%
2	54 100%	0 0%	0 0%	0 0%	54 100%
4	48 96%	0 0%	2 4%	0 0%	50 100%
8	96 93%	5 5%	1 1%	1 1%	103 100%
Total	244 381%	7 9%	5 9%	1 1%	257 400%

# Calibration tests without a bus extender

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# Calibration tests without a bus extender

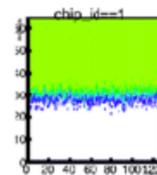
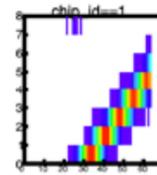
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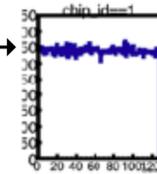
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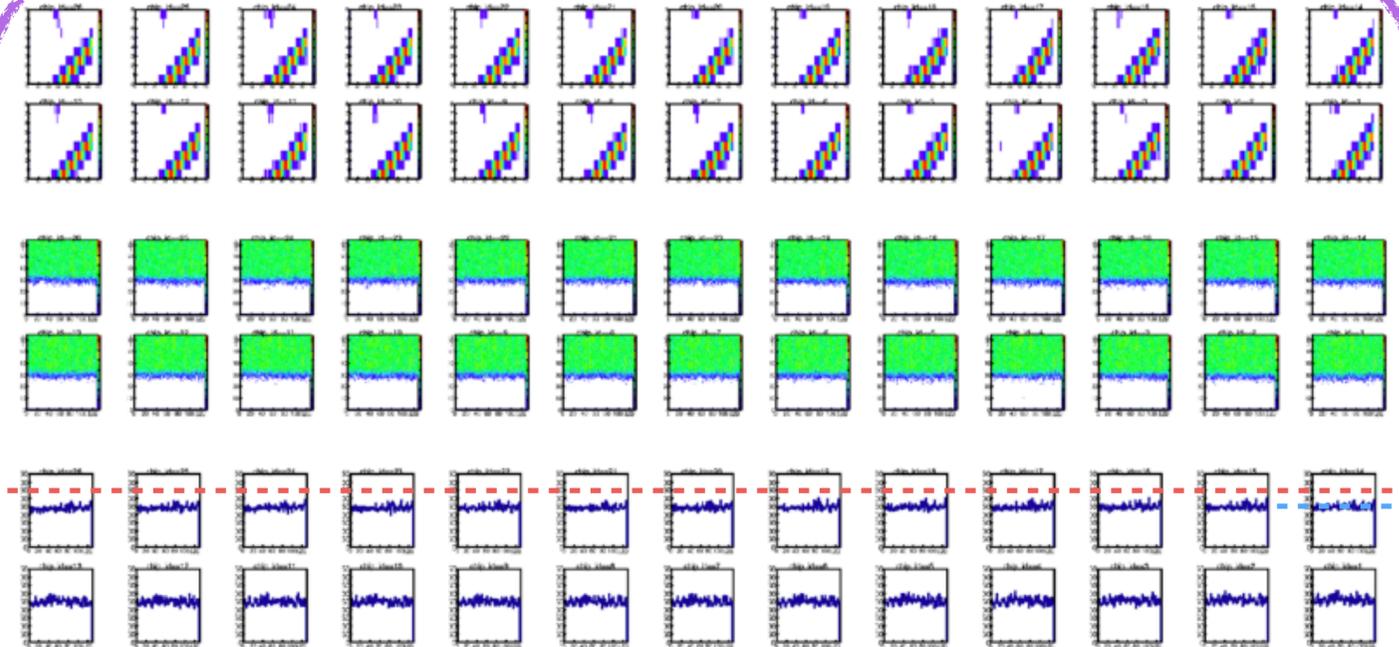
good samples



350 →

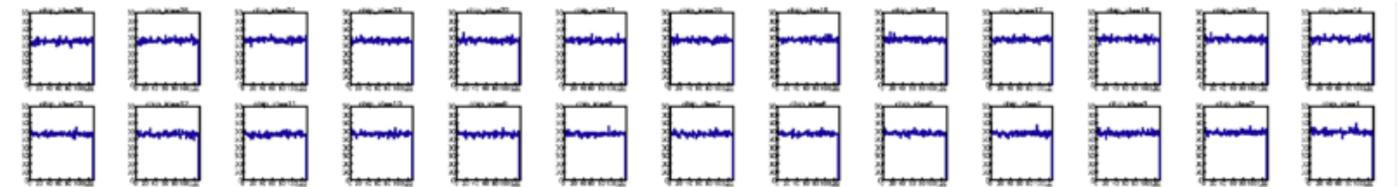


Bad/Dirty



The worst data tagged as Bad/Dirty.  
Only 250 entries / chip / channel obtained while about 350 in good measurements.

Fine



Data tagged as Fine.  
300 entries / chip / channel obtained while about 350 in good measurements.

# Calibration tests without a bus extender

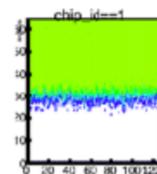
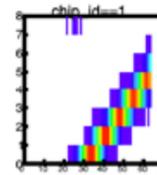
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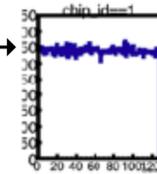
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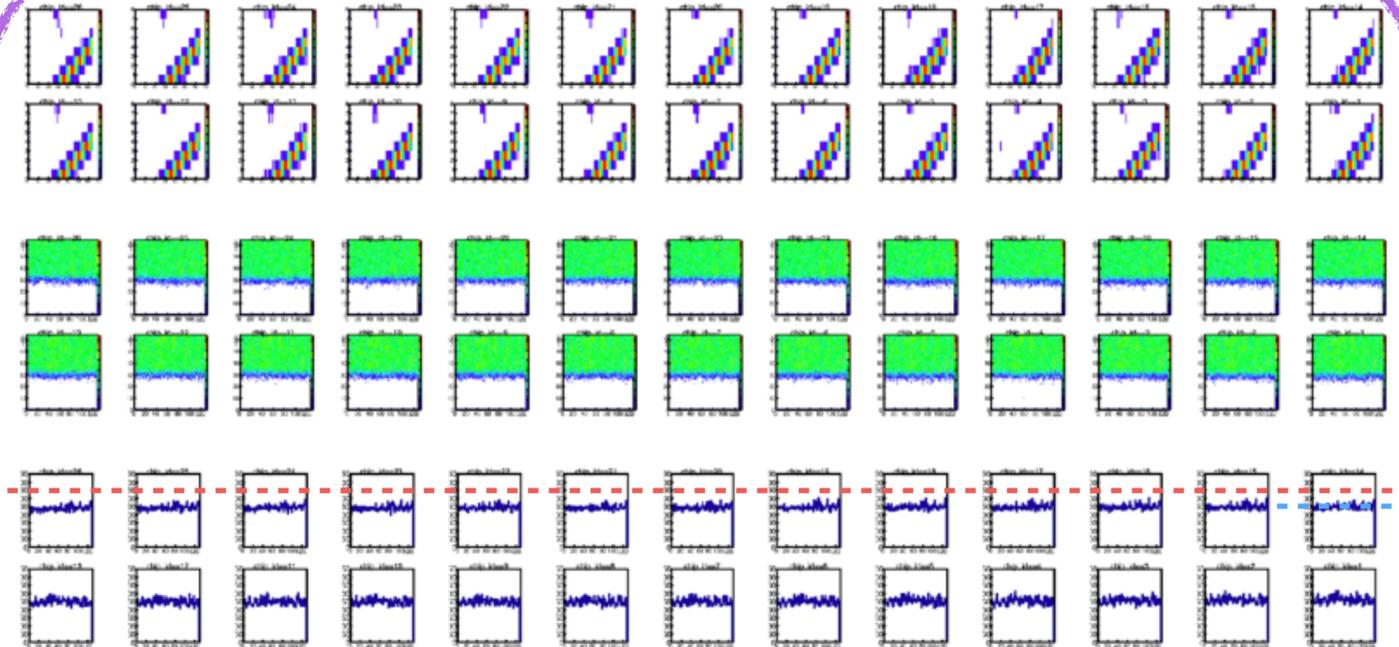
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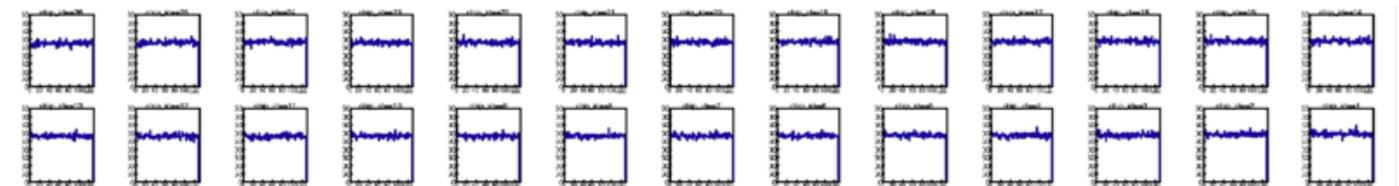


Bad/Dirty



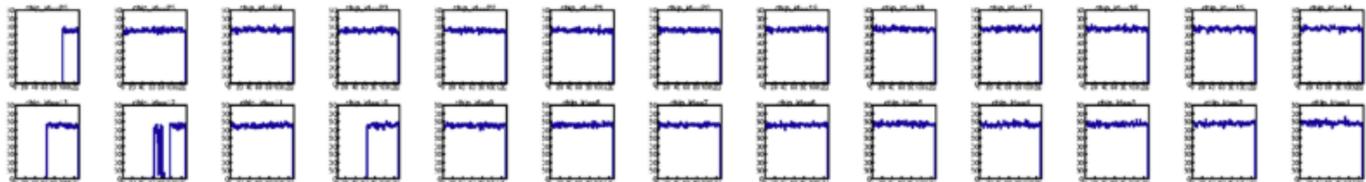
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Fine



Data tagged as Fine.  
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lost channels



The only run with missing channels (20210712-2140).

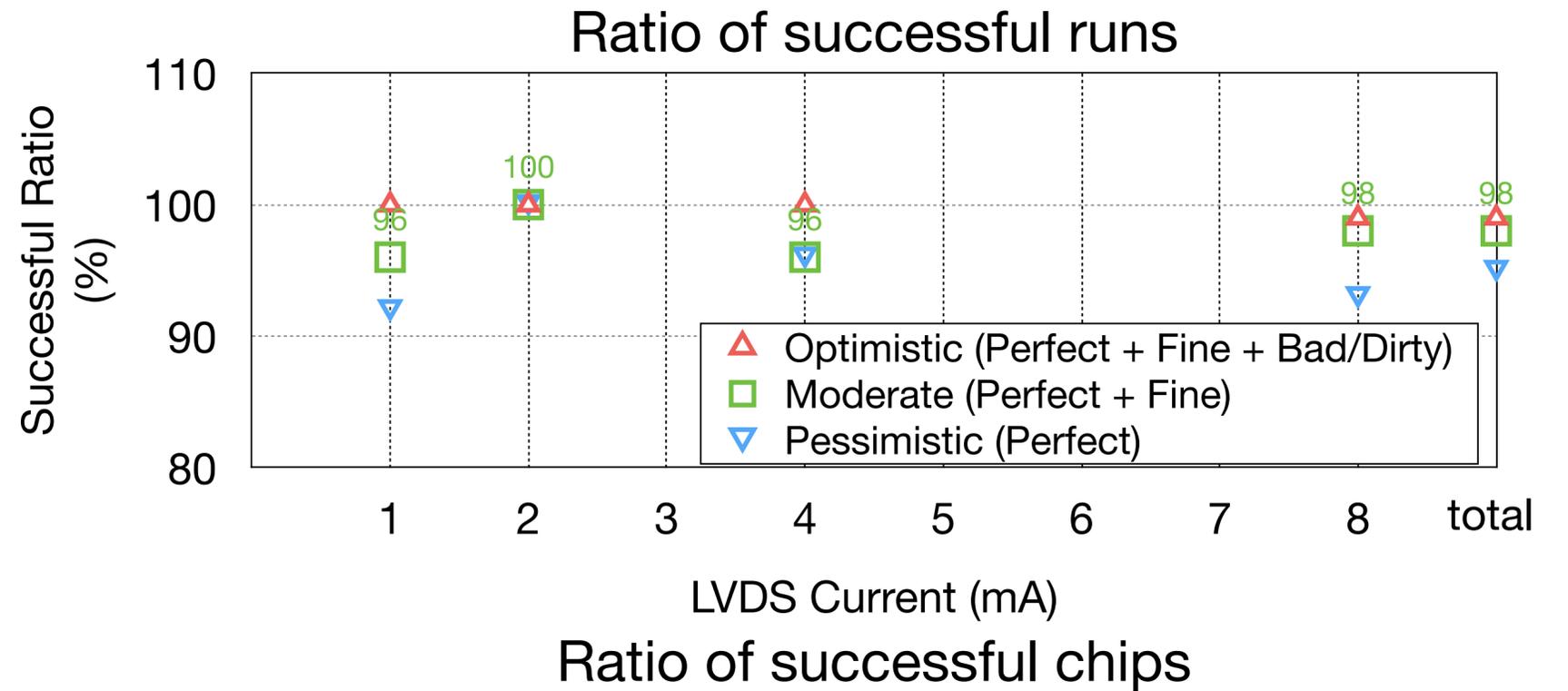
# Calibration tests without a bus extender

## Setup

- Ladder: PPB2-L4S
- Conversion cable: small 8
- ROC, port: SW5, C3
- Bus extender: not used

## Performance of ROC SW5 port C3

Quality LVDS (mA)	Perfect	Fine	Bad/Dirty	Half entry, lost channels	Total
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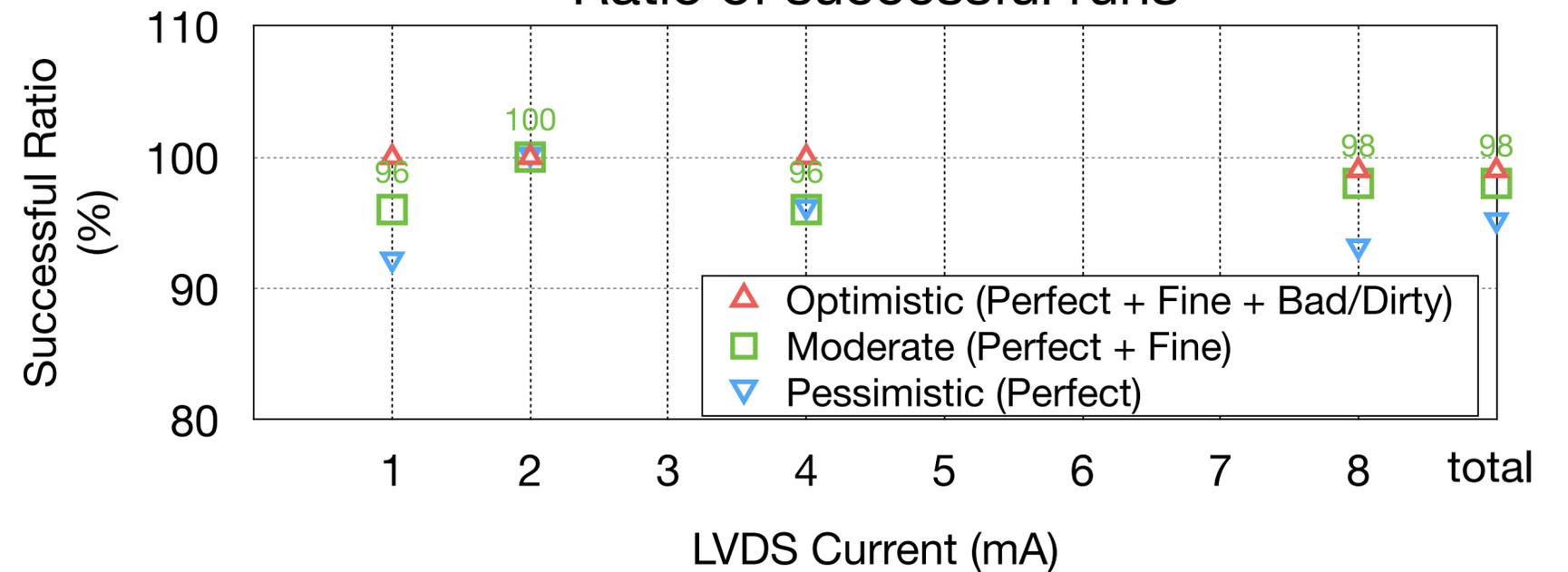
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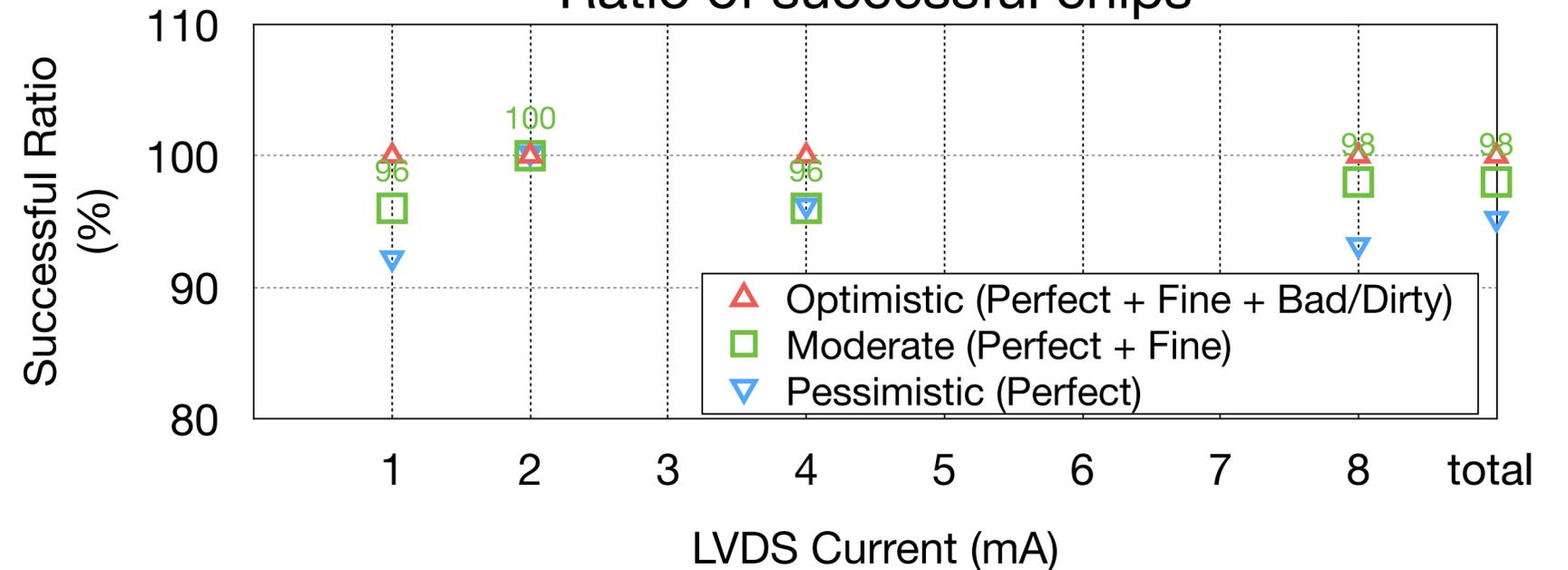
## Performance of ROC SW5 port C3 (chip-wise)

Quality LVDS (mA)	Perfect	Fine	Bad/Dirty	Half entry, lost channels	Total
1	1196 92%	52 4%	52 4%	0 0%	1300 100%
2	1404 100%	0 0%	0 0%	0 0%	1404 100%
4	1248 96%	0 0%	52 4%	0 0%	1300 100%
8	2496 94%	130 5%	26 1%	4 0%	2656 100%
<b>Total</b>	6344 95%	182 3%	130 2%	4 0%	6660 100%

## Ratio of successful runs



## Ratio of successful chips



# Calibration tests without a bus extender

## Setup

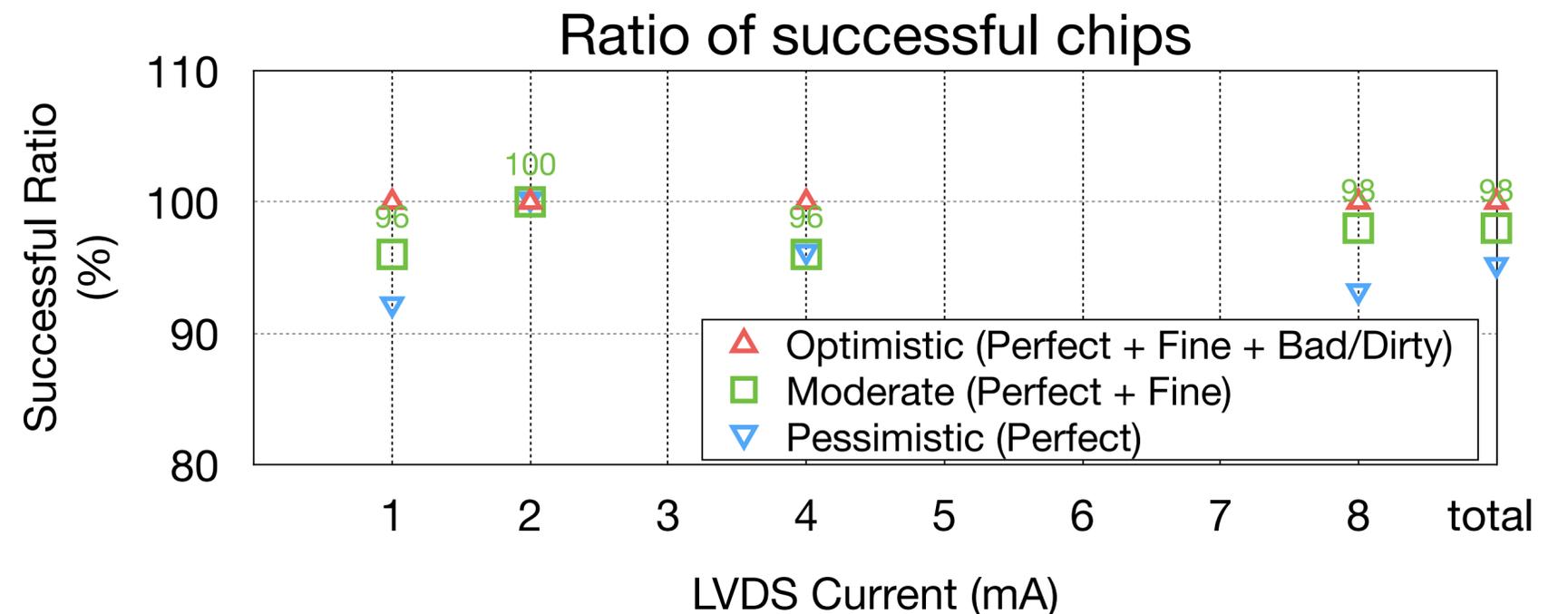
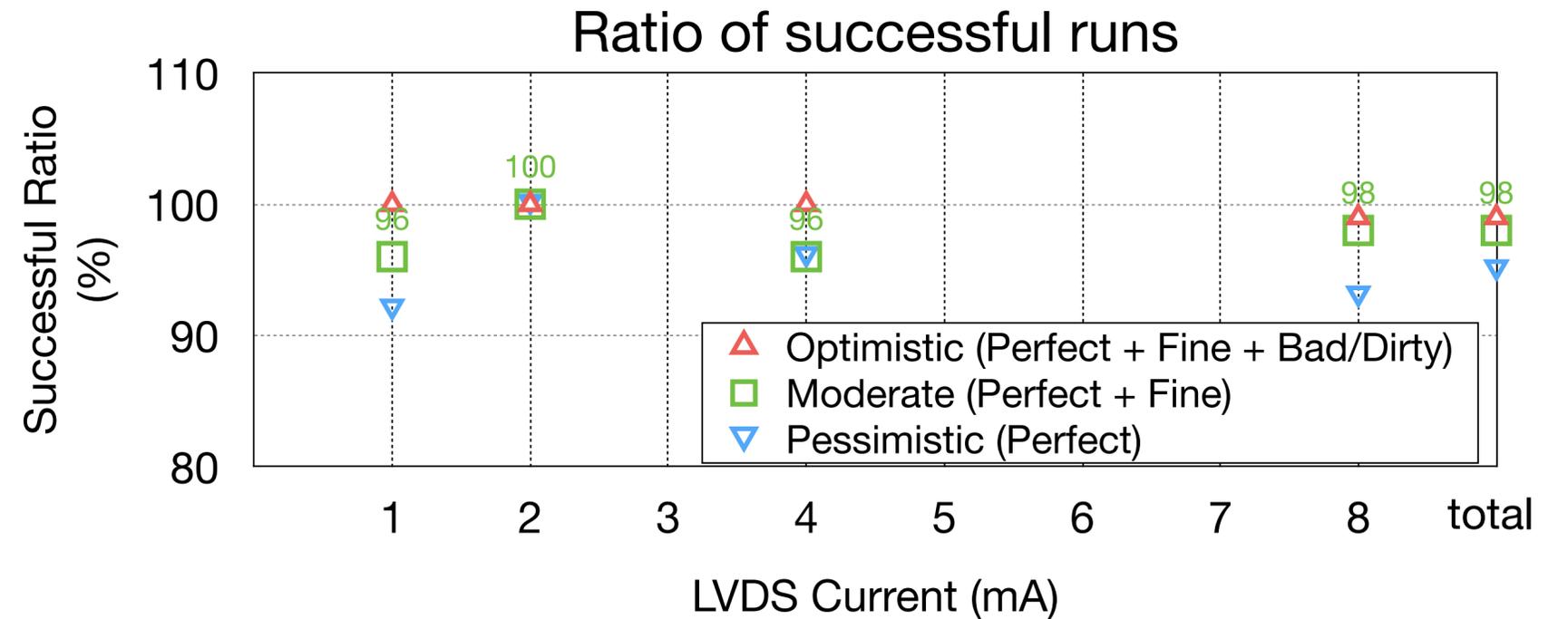
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Very stable and reliable operation with the setup without a bus extender achieved.

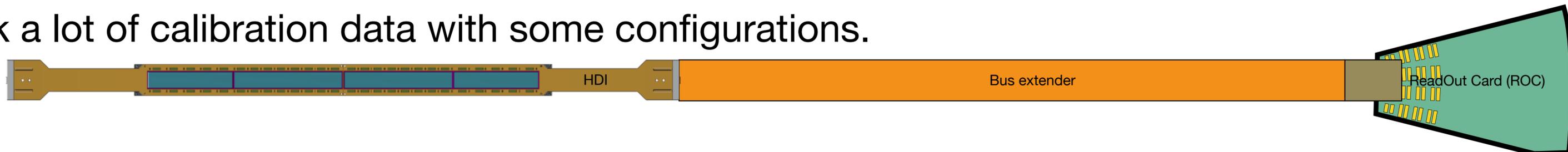
Ratios of successful runs and chips are independent from LVDS current.

# Calibration tests with a bus extender

Performance of ROC ports without a bus extender

	A1	A2	A3	C1	C2	C3
7	Good except chip25	no data	Good except chip1-5	Good except chip15 1.2m Prepro4 (130)	Good	Good
NW1	no data	no data	no data	Good new2 (120)	Good new2 (110) 1.2m Prepro3 (40)	Good new2 (170) 1.2m Prepro4 (40)
SW5	Good	Good 1.2m Prepro3 (230)	Good	Good	Good	Good 1.2m Prepro3 (600)

We took a lot of calibration data with some configurations.



# Calibration tests with ROC SW5 port-C3 and a bus extender

## Setup

- Ladder: PPB2-L4S
- Conversion cable: small 8
- ROC, port: SW5, C3
- Bus extender: 1.2 m Prepro3

Ratio of successful runs with the bus extender (ROC SW5-C3)

Quality LVDS (mA)	Perfect	Fine	Bad/Dirty	Half entry	Total
1	17	3	0	45	65
	26%	5%	0%	69%	100%
2	46	3	0	17	66
	70%	5%	0%	26%	100%
3	100	2	1	12	115
	87%	2%	1%	10%	100%
4	152	9	0	3	164
	93%	5%	0%	2%	100%
5	109	4	1	1	115
	95%	3%	1%	1%	100%
6	13	0	0	1	14
	93%	0%	0%	7%	100%
7	14	1	0	0	15
	93%	7%	0%	0%	100%
8	60	4	0	0	64
	94%	6%	0%	0%	100%
$\sum_4^8$	348	18	1	5	372
	94%	5%	0%	1%	100%

# Calibration tests with ROC SW5 port-C3 and a bus extender

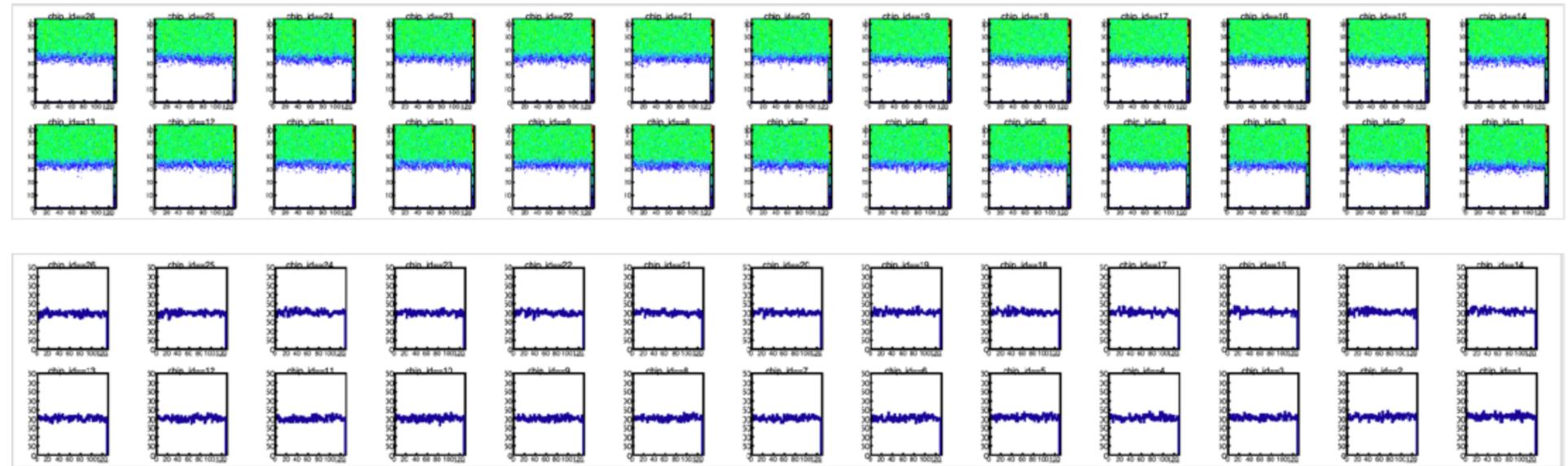
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Ratio of successful runs with the bus extender (ROC SW5-C3)

Quality LVDS (mA)	Perfect	Fine	Bad/Dirty	Half entry	Total
1	17 26%	3 5%	0 0%	45 69%	65 100%
2	46 70%	3 5%	0 0%	17 26%	66 100%
3	100 87%	2 2%	1 1%	12 10%	115 100%
4	152 93%	9 5%	0 0%	3 2%	164 100%
5	109 95%	4 3%	1 1%	1 1%	115 100%
6	13 93%	0 0%	0 0%	1 7%	14 100%
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$\sum_4^8$	348 94%	18 5%	1 0%	5 1%	372 100%

riken\_fphx\_raw\_20210710-2136\_0.dat (LVDS=5mA)



only ~200 entry/ch/chip (normally ~300 entry/ch/chip) was obtained

# Calibration tests with ROC SW5 port-C3 and a bus extender

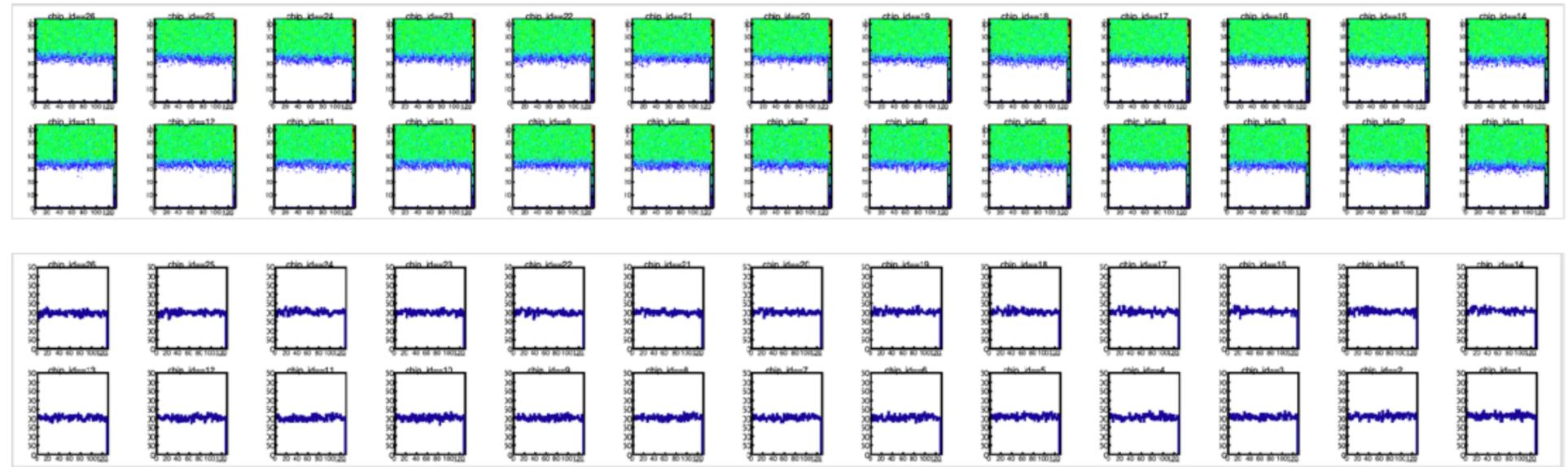
## Setup

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Ratio of successful runs with the bus extender (ROC SW5-C3)

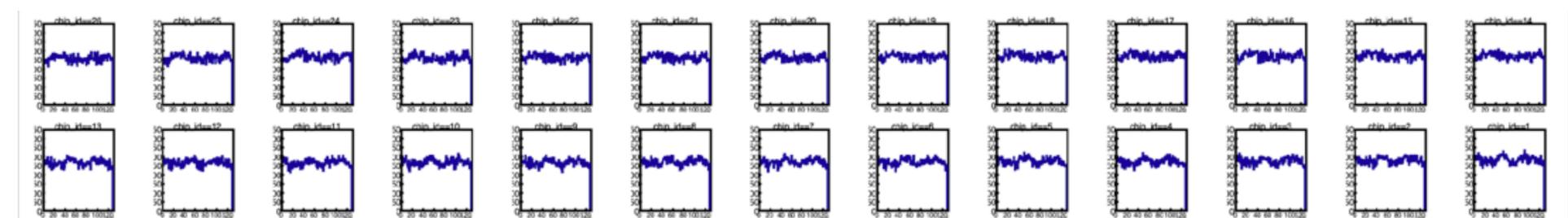
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riken\_fphx\_raw\_20210710-2136\_0.dat (LVDS=5mA)



only ~200 entry/ch/chip (normally ~300 entry/ch/chip) was obtained

riken\_fphx\_raw\_20210711-1113\_0.dat (LVDS=3mA)



dists. are waving, only 250~300 entry/ch/chip was taken

# Calibration tests with ROC SW5 port-C3 and a bus extender

## Setup

- Ladder: PPB2-L4S
- Conversion cable: small 8
- ROC, port: SW5, C3
- Bus extender: 1.2 m Prepro3

Ratio of successful runs with the bus extender (ROC SW5-C3)

Quality LVDS (mA)	Perfect	Fine	Bad/Dirty	Half entry	Total
1	17 26%	3 5%	0 0%	45 69%	65 100%
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$\sum_4^8$	348 94%	18 5%	1 0%	5 1%	372 100%

## Situation at NWU

### Setup

- Date: Apri;/5/2021-April/6/2021
- Ladder: PPB2-L5N
- ROC, port: #9, C3 (2.8 & 3.0 V regulators)
- Conversion cable: large #3
- Bus extender: new2 (line for chip24 & chip26 shorten)
- LVDS: 7 or 8 mA (?)

#Runs: 60

Perfect: 49

Half entry: 11

#half entry chip: 15

Runs: 49 / 60 → 82%

Chip :  $(49 \times 24 - 15) / (49 \times 24)$  chips → 99%

It's not too bad, but the RIKEN testbench encounters less half entry phenomena than NWU's. As far as I remember, operation with LVDS current less than 7 mA at NWU has so many half entry chips.

# Calibration tests with ROC SW5 port-C3 and a bus extender

## Setup

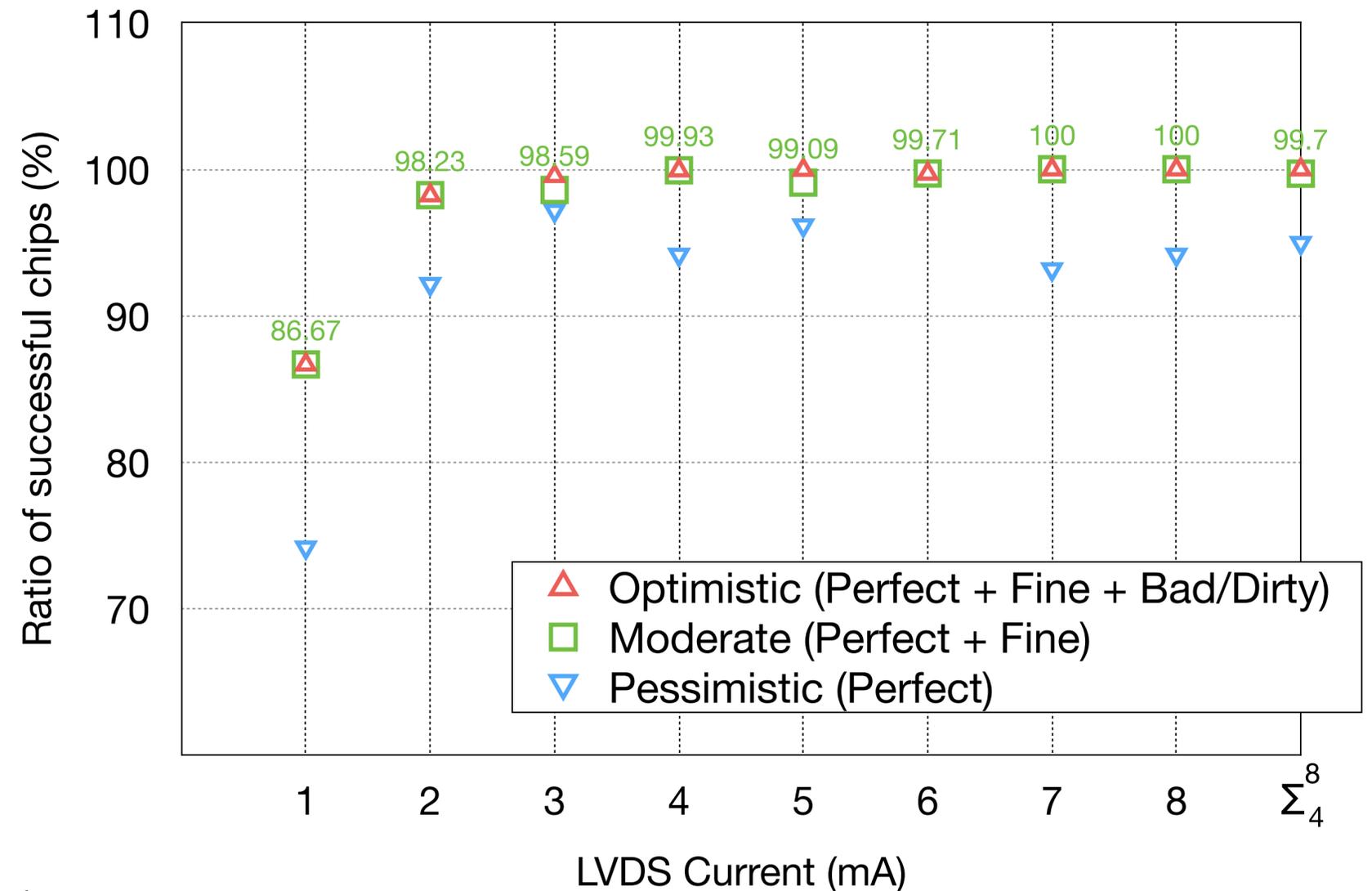
- Ladder: PPB2-L4S
- Conversion cable: small 8
- ROC, port: SW5, C3
- Bus extender: 1.2 m Prepro3

Ratio of successful chips with the bus extender (ROC SW5-C3)

Quality LVDS (mA)	Perfect	Fine	Bad/Dirty	Half entry	Total
1	442	78	0	80	600
	74%	13%	0%	13%	100%
2	1196	78	0	23	1297
	92%	6%	0%	2%	100%
3	2600	52	26	12	2690
	97%	2%	1%	0%	100%
4	3952	234	0	3	4189
	94%	6%	0%	0%	100%
5	2834	104	26	1	2965
	96%	4%	1%	0%	100%
6	338	0	0	1	339
	100%	0%	0%	0%	100%
7	364	26	0	0	390
	93%	7%	0%	0%	100%
8	1560	104	0	0	1664
	94%	6%	0%	0%	100%
$\sum_4^8$	9048	468	26	5	9547
	94.8%	4.9%	0.3%	0.1%	100%

← more chips than 3 INTT barrels

## Ratio of successful chips (ROC SW5, C3)



# Calibration tests with a bus extender

## Setup

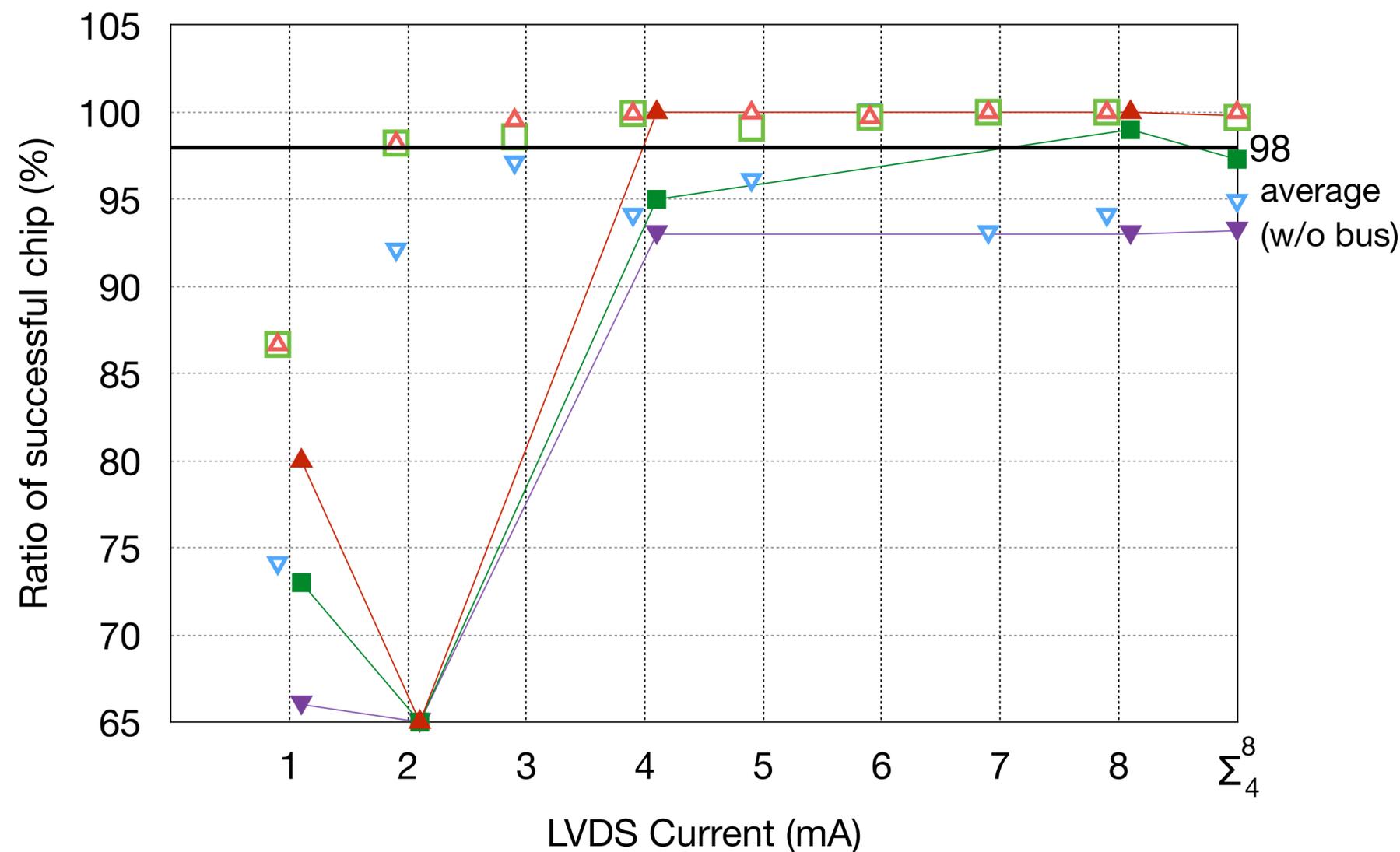
- Ladder: PPB2-L4S
- Conversion cable: small 8
- ROC, port: SW5, A2
- Bus extender: 1.2 m Prepro3

## Ratio of successful chips (ROC SW5, A2)

Quality LVDS (mA)	Perfect	Fine	Bad/Dirty	Half entry	Total
1	234	26	26	70	356
	66%	7%	7%	20%	100%
2	156	0	0	83	239
	65%	0%	0%	35%	100%
3					
4	1092	26	52	5	1175
	93%	2%	4%	0%	100%
5					
6					
7					
8	1846	104	26	1	1977
	93%	5%	1%	0%	100%
4mA +8mA	2938	130	78	6	3152
	93.2%	4.1%	2.5%	0.2%	100%

- △ C3 Optimistic (Perfect + Fine + Bad/Dirty)
- C3 Moderate (Perfect + Fine)
- ▽ C3 Pessimistic (Perfect)
- ▲ A2 Optimistic (Perfect + Fine + Bad/Dirty)
- A2 Moderate (Perfect + Fine)
- ▼ A2 Pessimistic (Perfect)

## Ratio of successful chips



# Calibration tests with a bus extender

## Setup

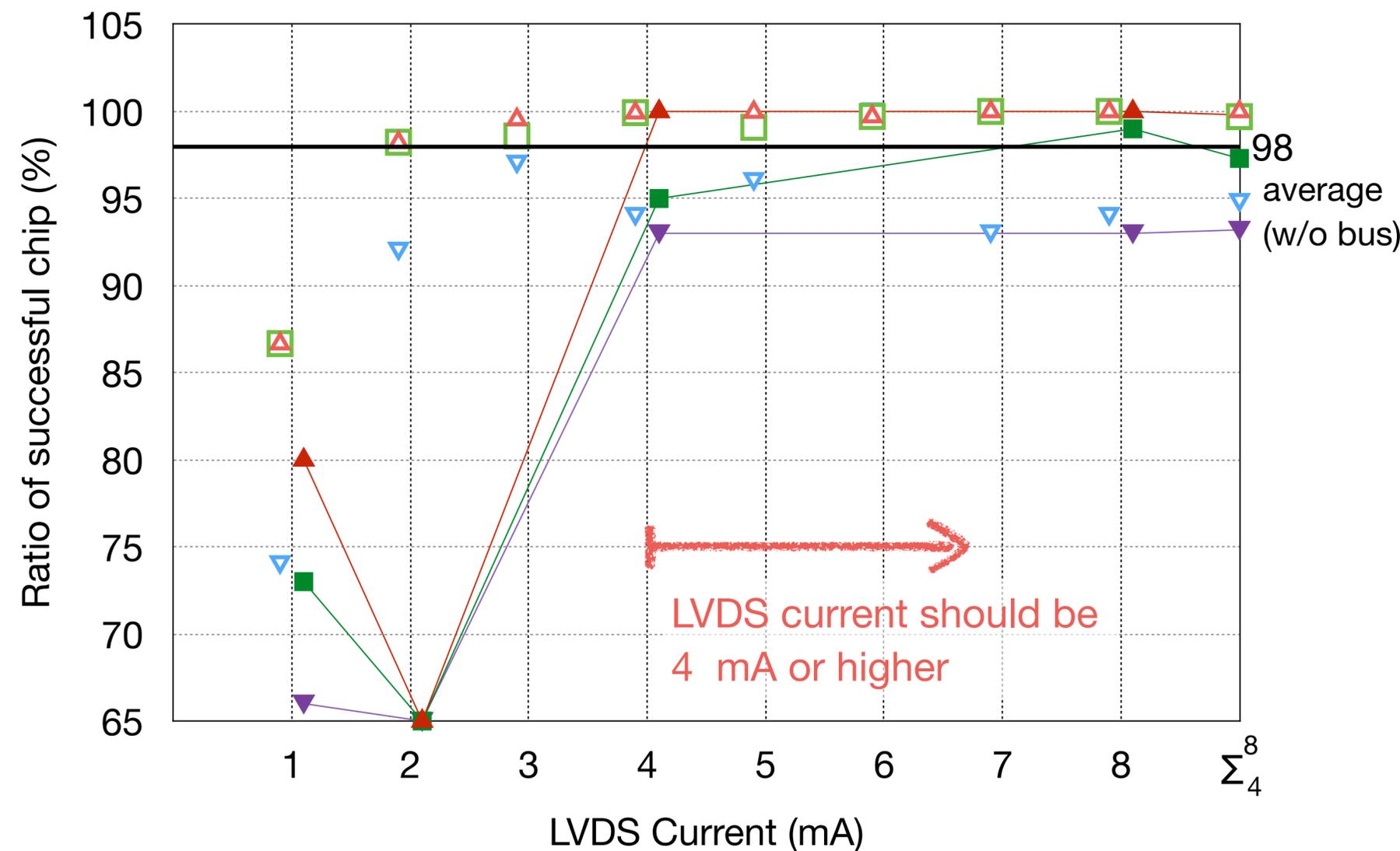
- Ladder: PPB2-L4S
- Conversion cable: small 8
- ROC, port: SW5, A2
- Bus extender: 1.2 m Prepro3

## Ratio of successful chips (ROC SW5, A2)

Quality LVDS (mA)	Perfect	Fine	Bad/Dirty	Half entry	Total
1	234	26	26	70	356
	66%	7%	7%	20%	100%
2	156	0	0	83	239
	65%	0%	0%	35%	100%
3					
4	1092	26	52	5	1175
	93%	2%	4%	0%	100%
5					
6					
7					
8	1846	104	26	1	1977
	93%	5%	1%	0%	100%
4mA +8mA	2938	130	78	6	3152
	93.2%	4.1%	2.5%	0.2%	100%

- △ C3 Optimistic (Perfect + Fine + Bad/Dirty)
- C3 Moderate (Perfect + Fine)
- ▽ C3 Pessimistic (Perfect)
- ▲ A2 Optimistic (Perfect + Fine + Bad/Dirty)
- A2 Moderate (Perfect + Fine)
- ▼ A2 Pessimistic (Perfect)

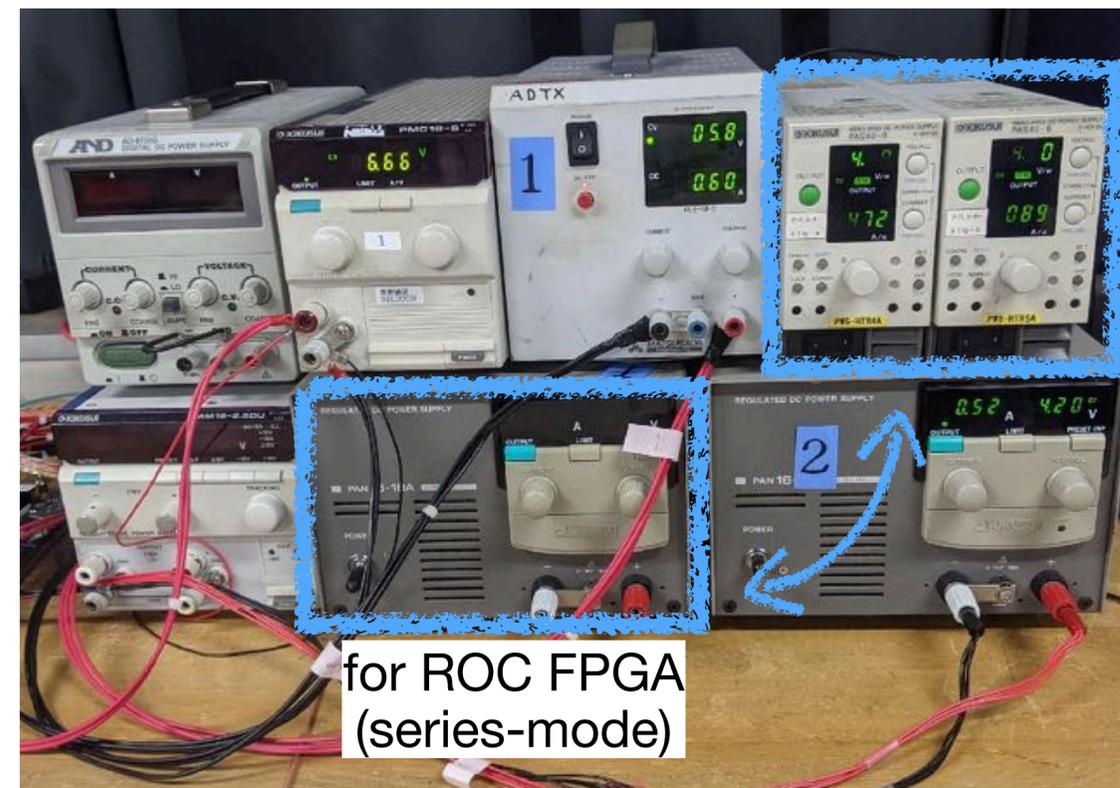
## Ratio of successful chips



# Difference b/w NWU and RIKEN testbenches and plans

Before starting RIKEN testbench, all components (FEM, FEM-IB, one of ROC(7?), conversion cable(s?), bus extender “new2”, cables for power supplies, optical fibers, bias cable) were transported to NWU, and calibration tests (maybe w/o?) a bus extender were performed. People didn't find special differences at that time, so RIKEN testbench is basically the same as NWU's. For the moment, we know the difference of power supplies for ROC FPGA at NWU (switching) and RIKEN (linear). Replacement of the linear power supply at RIKEN to switching one didn't reproduce the half entry issue as NWU faces.

T. Kondo will come to RIKEN next week to measure eye-diagrams. T. Hachiya and I. Nakagawa are working for the FPHX readbacker and ROC FPGA. We may send NWU testbench to RIKEN for tests.



Power supplies  
(switching-mode)

for ROC FPGA  
(series-mode)

# Summary

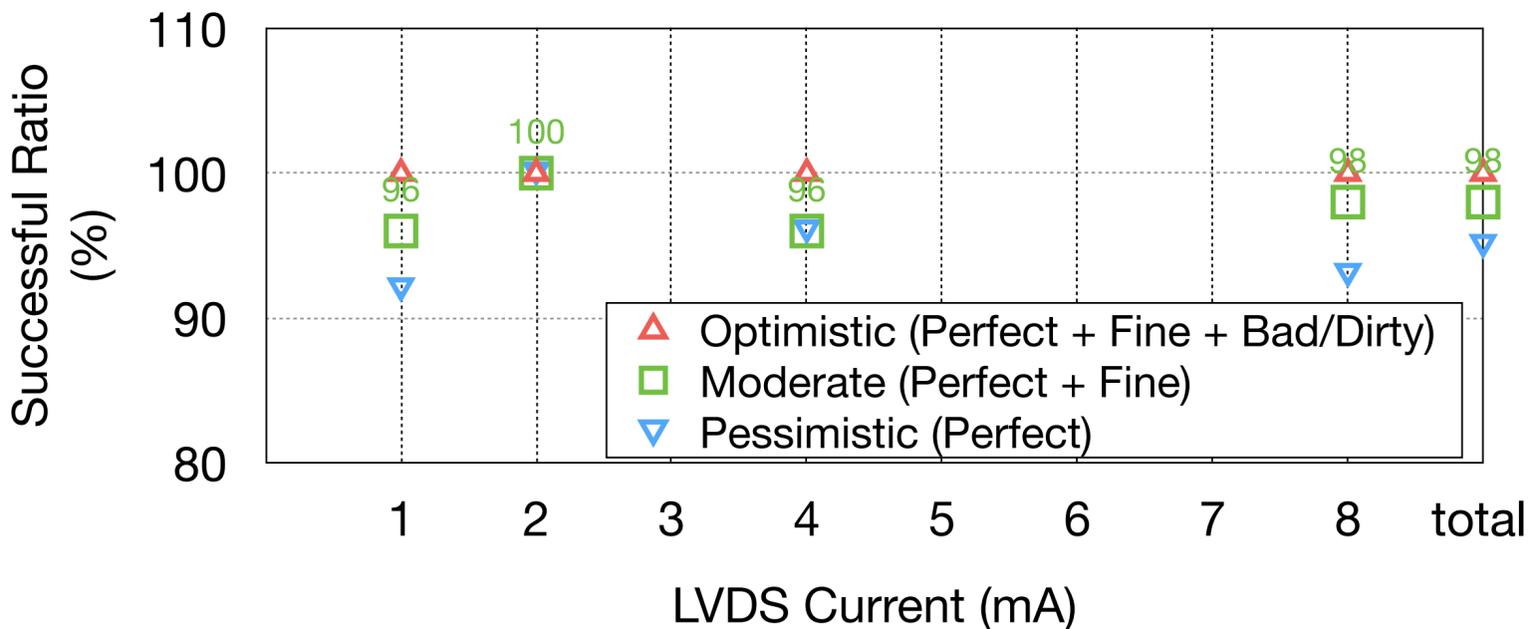
Calibration tests were performed very stably with various configurations.

Chips with only half entry rarely appear at RIKEN testbench about 0.1%. The issue may depend on a setup.

About 5% of chips have less data ~300 entries/ch than usual (350/ch).

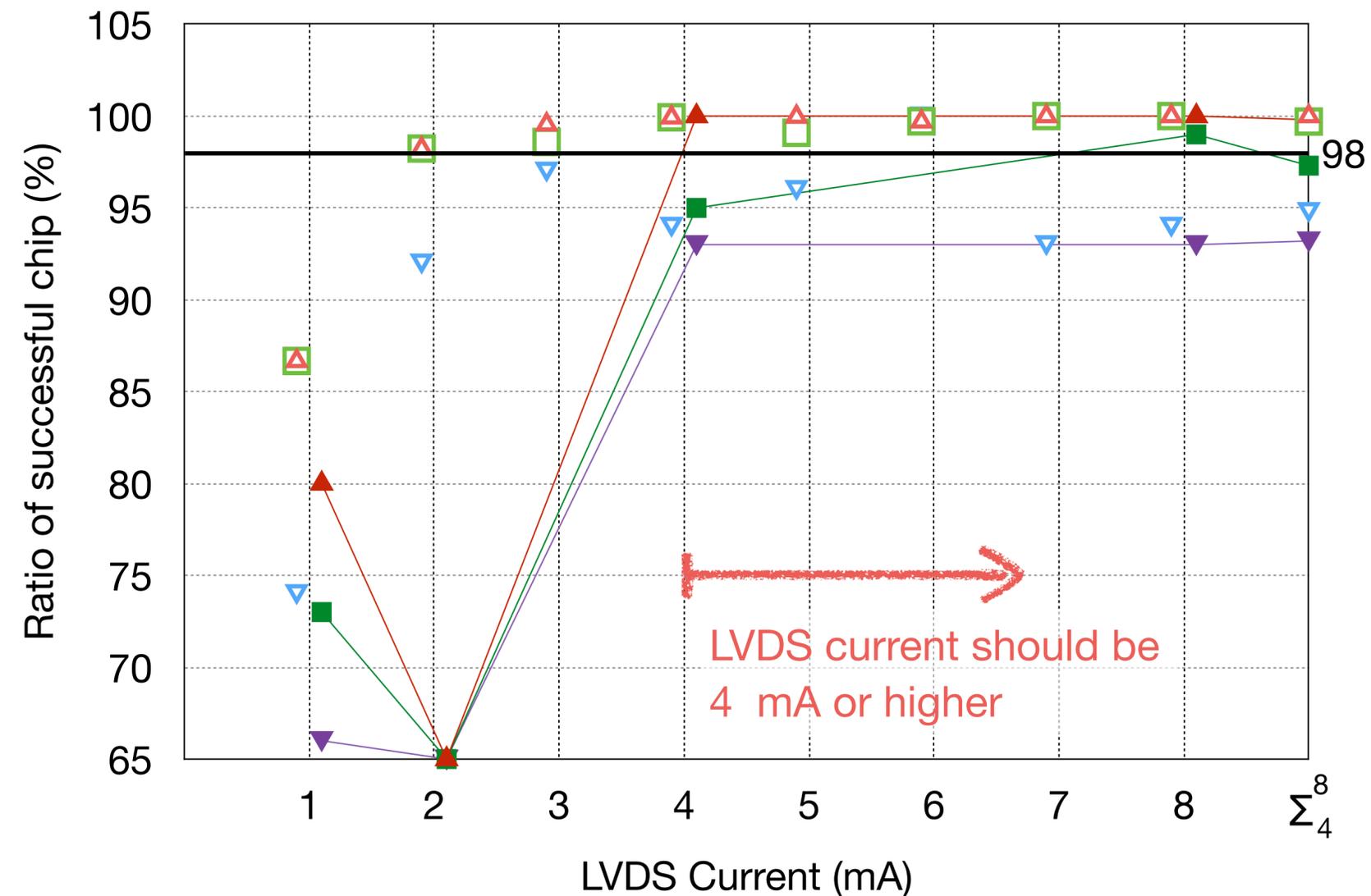
Further investigations are planned.

Ratio of successful chips (w/o bus extender)



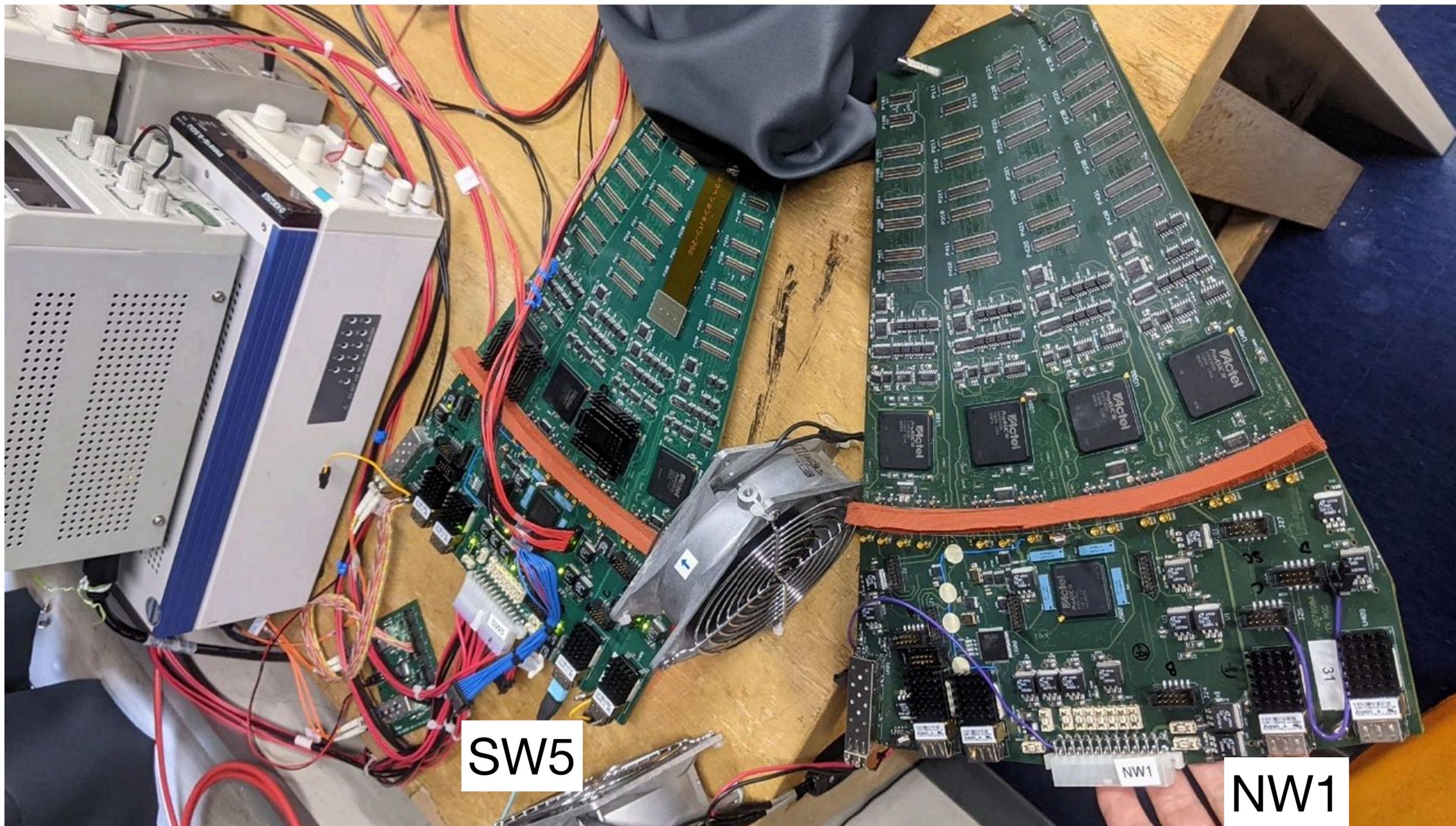
- △ C3 Optimistic (Perfect + Fine + Bad/Dirty)
- C3 Moderate (Perfect + Fine)
- ▽ C3 Pessimistic (Perfect)
- ▲ A2 Optimistic (Perfect + Fine + Bad/Dirty)
- A2 Moderate (Perfect + Fine)
- ▼ A2 Pessimistic (Perfect)

Ratio of successful chips (with bus extender)

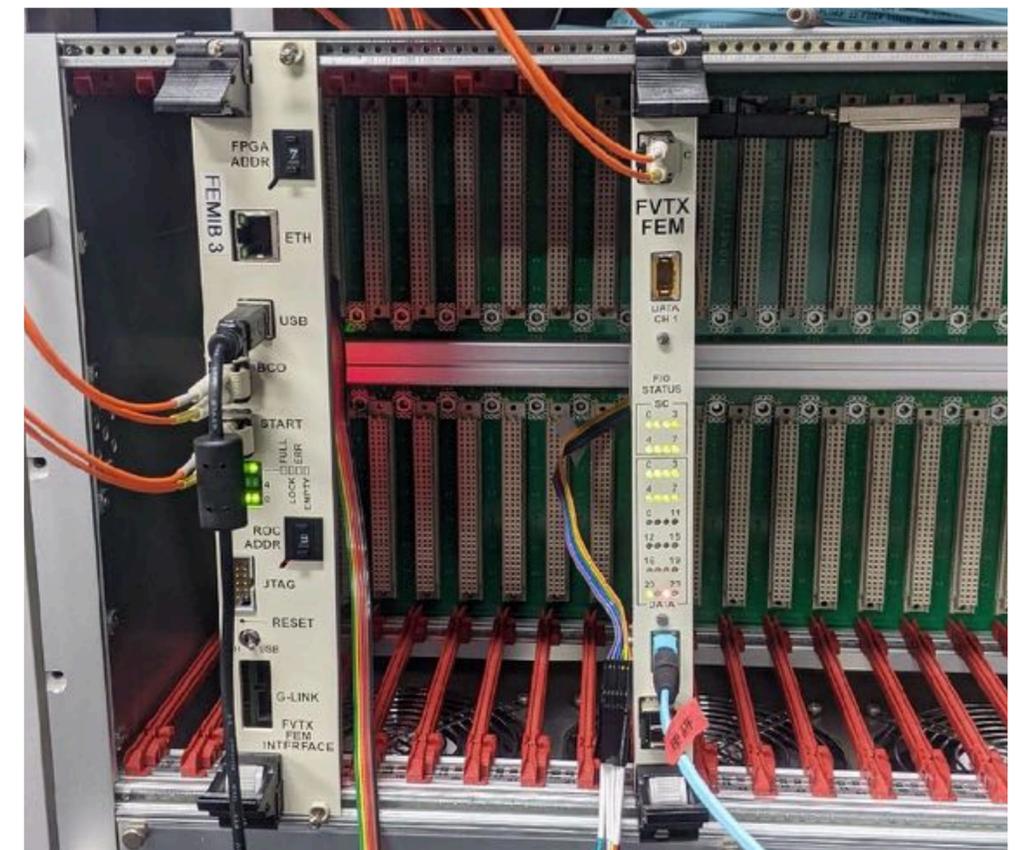
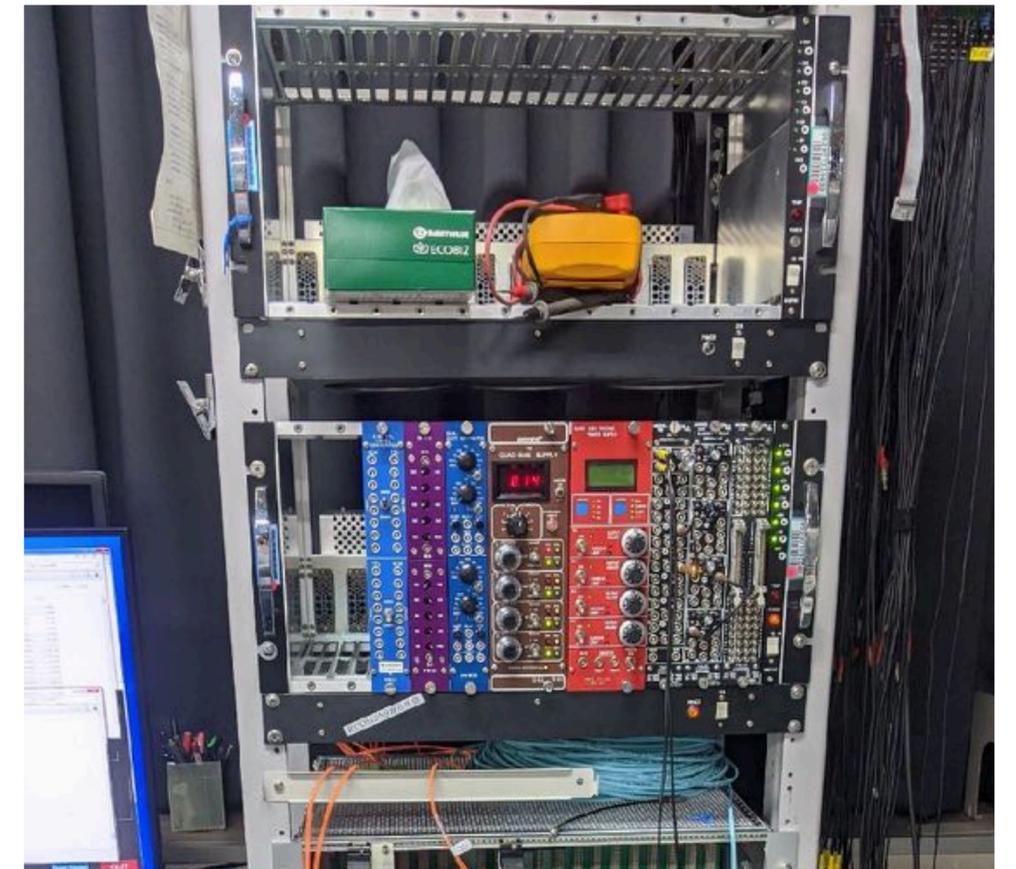
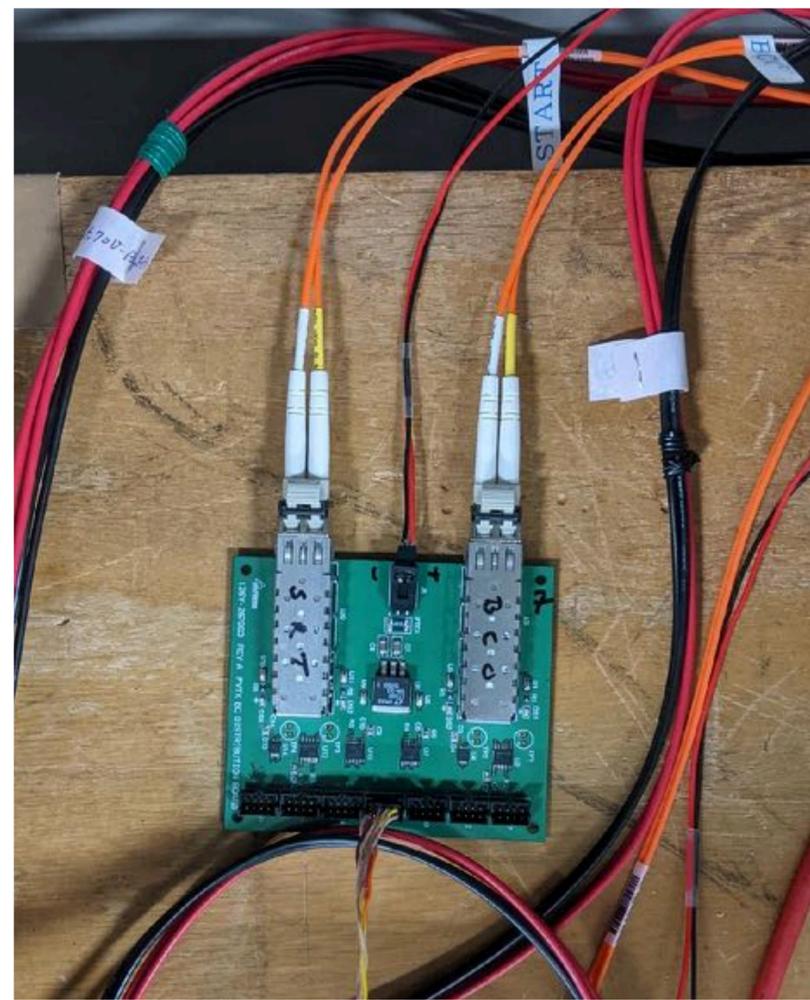
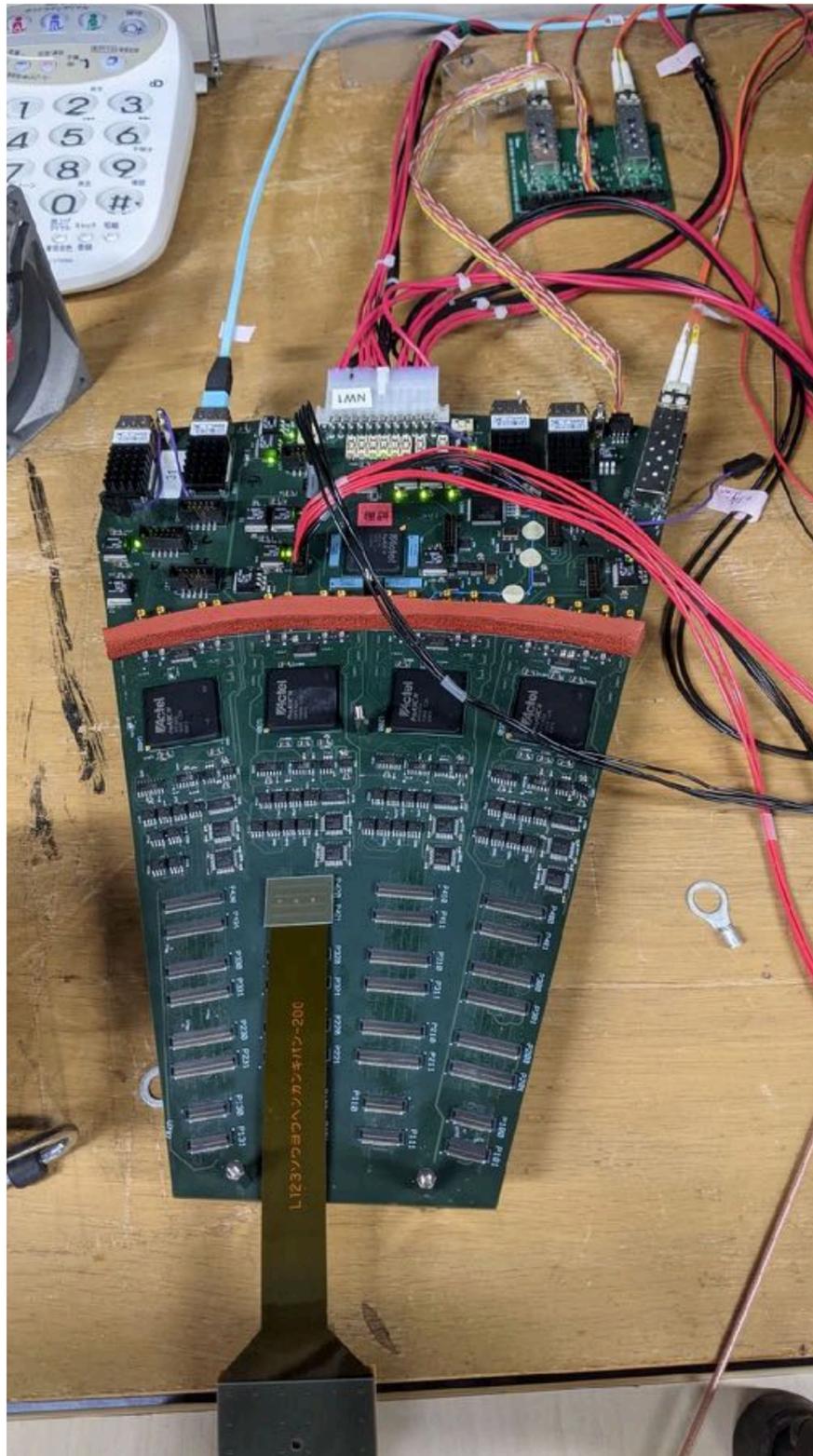


**backup**

# ROC SW5



# RIKEN testbench



# sPHENIX wiki > INTT > RIKEN Test Bench

The screenshot shows a MediaWiki page titled "RIKEN Test Bench" on the sPHENIX wiki. The page includes a navigation menu on the left with links to various detector components and tools. The main content area features a title, a paragraph about the start date, a "Log notes" section with a note about scanning frequency, and a "Pictures" gallery with seven images: "Before", "when it's done", "ROC (NW1)", "BCO distributing board", "Power supplies", "NIM and VME crates", and "PC display". The page footer contains a last edit timestamp and a "Powered By MediaWiki" logo.

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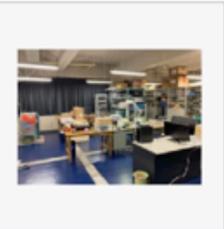
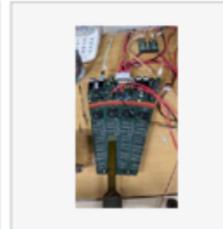
## RIKEN Test Bench

started (again?) in June/15/2021.

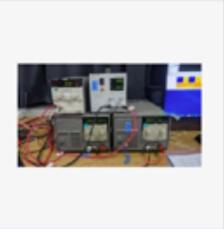
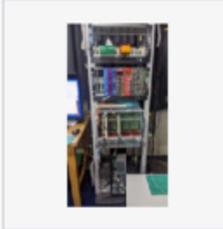
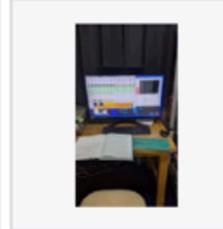
**Log notes** [\[edit\]](#) [\[edit source\]](#)

Let's scan it once a week. Since it's slightly larger than A4 paper, you can set the size as 220 mm x 300 mm manually and scan it page by page.

**Pictures** [\[edit\]](#) [\[edit source\]](#)

Before      when it's done      ROC (NW1)      BCO distributing board

Power supplies      NIM and VME crates      PC display

This page was last edited on 1 July 2021, at 03:38.

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